Generalization Theory for Deep Learning



Basic version: finite hypothesis class

Finite hypothesis class: with probability $1 - \delta$ over the choice of a training set of size *n*, for a bounded loss ℓ , we have

$$\sup_{f \in \mathscr{F}} \left| \frac{1}{n} \sum_{i=1}^{n} \ell(f(x_i), y_i) - \mathbb{E}_{(x, y) \sim D} \left[\ell(f(x), y) \right] \right| = O\left(\sqrt{\frac{\log |\mathscr{F}| + \log 1/\delta}{n}}\right)$$

VC-Dimension

Motivation: Do we need to consider **every** classifier in \mathcal{F} ? Intuitively, **pattern of classifications** on the training set should suffice. (Two predictors that predict identically on the training set should generalize similarly).

Let
$$\mathscr{F} = \{f : \mathbb{R}^d \to \{+1, -1\}\}$$
 be a class of binary classifiers.

The growth function $\Pi_{\mathscr{F}} : \mathbb{N} \to \mathbb{F}$ is defined as:

$$\Pi_{\mathcal{F}}(m) = \max_{(x_1, x_2, \dots, x_m)} \left| \left\{ (f(x_1), f(x_2), \dots, f(x_m)) \mid f \in \mathcal{F} \right\} \right|.$$

The VC dimension of \mathscr{F} is defined as: $\operatorname{VCdim}(\mathscr{F}) = \max\{m : \Pi_{\mathscr{F}}(m) = 2^m\}.$

VC-dimension Generalization bound

Theorem (Vapnik-Chervonenkis): with probability $1 - \delta$ over the choice of a training set, for a bounded loss ℓ , we have

$$\sup_{f \in \mathscr{F}} \left| \frac{1}{n} \sum_{i=1}^{n} \mathscr{\ell}(f(x_i), y_i) - \mathbb{E}_{(x, y) \sim D} \left[\mathscr{\ell}(f(x), y) \right] \right| = O\left(\sqrt{\frac{\mathsf{VCdim}(\mathscr{F})\log n + \log 1/\delta}{n}}\right)$$

Examples:

- Linear functions: VC-dim = O(dimension)
- Neural network: VC-dimension of fully-connected net with width W and H layers is $\Theta(WH)$ (Bartlett et al., '17).

Problems with VC-dimension bound

- 1. In over-parameterized regime, bound >> 1.
- 2. Cannot explain the random noise phenomenon:
 - Neural networks that fit random labels and that fit true labels have the same VC-dimension.



PAC Bayesian Generalization Bounds

Setup: Let *P* be a prior over function in class \mathscr{F} , let *Q* be the posterior (after algorithm's training).

Theorem: with probability $1 - \delta$ over the choice of a training set, for a bounded loss ℓ , we have

$$\sup_{\mathbf{x} \in \mathscr{F}} \left| \frac{1}{n} \sum_{i=1}^{n} \ell(f(x_i), y_i) - \mathbb{E}_{(x,y) \sim D} \left[\ell(f(x), y) \right] \right| = O\left(\sqrt{\frac{KL(Q \mid \downarrow P) + \log 1/\delta}{n}} \right)$$

$$P\left(\mathcal{W}_{1,j}^{i} \right) \sim \mathcal{M}(0, 1) \qquad \text{data - dependent}$$

$$\int \mathcal{W}_{1,j}^{i} \int \mathcal{M}(0, 1) \qquad \text{data - dependent}$$

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Rademacher Complexity

Intuition: how well can a classifier class fit random noise?

(Empirical) Rademacher complexity: For a training set $S = \{x_1, x_2, \dots, x_n\}$, and a class \mathscr{F} , denote: $\begin{pmatrix} b_1 & \dots & b_n \end{pmatrix}$ $\hat{R}_n(S) = \mathbb{E}_{\sigma} \sup_{f \in \mathscr{F}} \sum_{i=1}^n \sigma_i f(x_i)$. Virially will where $\sigma_i \sim \text{Unif}\{+1, -1\}$ (Rademacher R.V.).

(Population) Rademacher complexity:

$$R_n = \mathbb{E}_{S}\left[\hat{R}_n(s)\right].$$

Rademacher Complexity Generalization Bound

Theorem: with probability $1 - \delta$ over the choice of a training set, for a bounded loss ℓ , we have

$$\sup_{f \in \mathscr{F}} \left| \frac{1}{n} \sum_{i=1}^{n} \mathscr{E}(f(x_i), y_i) - \mathbb{E}_{(x, y) \sim D} \left[\mathscr{E}(f(x), y) \right] \right| = O\left(\frac{\hat{R}_n}{n} + \sqrt{\frac{\log 1/\delta}{n}}\right)$$

and

$$\sup_{f \in \mathscr{F}} \left| \frac{1}{n} \sum_{i=1}^{n} \ell(f(x_i), y_i) - \mathbb{E}_{(x, y) \sim D} \left[\ell(f(x), y) \right] \right| = O\left(\frac{R_n}{n} + \sqrt{\frac{\log 1/\delta}{n}}\right)$$

Kernel generalization bound Use Rademacher complexity theory, we can obtain a generalization bound $O(\sqrt{y^{T}(H^{*})^{-1}y/n})$ where $y \in \mathbb{R}^{n}$ are *n* labels, and $H^{*} \in \mathbb{R}^{n \times n}$ is the kernel (e.g., NTK) matrix.



Norm-based Rademacher complexity bound NOLU: P=1 **Theorem:** If the activation function is σ is ρ -Lipschitz. Let $\mathcal{F} = \{ x \mapsto W_{H+1} \sigma(W_h \sigma(\cdots \sigma(W_1 x) \cdots), \|W_h^T\|_{1,\infty} \le B \forall h \in [H] \}$ then $R_n(\mathcal{S}) \le \|X^{\mathsf{T}}\|_{2,\infty} (2\rho B)^{H+1} \sqrt{2 \ln d}$ where $X = [x_1, \dots, x_n] \in \mathbb{R}^{d \times n}$ is the input data matrix. $\begin{cases} \|X^{T}\|_{2, W} &= \max \|X_{1}^{*}\|_{2} \\ \|X_{1}^{T}\|_{2, W} &= \max \|X_{1}^{*}\|_{2} \\ \|W_{1}^{T}\|_{1, W} &= \max \|W_{1}^{*}\|_{1} \\ \|W_{1}^{T}\|_{1} \\ \|W_{1}^{T}\|_{1, W} &= \max \|W_{1}^{*}\|_{1} \\ \|W_{1}^{T}\|_{1} \\ \|W_{1$

Comments on generalization bounds

- When plugged in real values, the bounds are rarely non-trivial (i.e., smaller than 1)
- "Fantastic Generalization Measures and Where to Find them" by Jiang et al. '19 : large-scale investigation of the correlation of extant generalization measures with true generalization.



Image credits to Andrej Risteski

Comments on generalization bounds

- Uniform convergence may be unable to explain generalization of deep learning [Nagarajan and Kolter, '19]
 - Uniform convergence: a bound for all $f\in \mathscr{F}$
 - Exists example that 1) can generalize, 2) uniform convergence fails.

- Rates:
 - Most bounds: $1/\sqrt{n}$.
 - Local Rademacher complexity: 1/n.

Separation between NN and kernel

 For approximation and optimization, neural network has no advantage over kernel. Why NN gives better performance: generalization.

- [Allen-Zhu and Li '20] Construct a class of functions \mathscr{F} such that y = f(x) for some $f \in \mathscr{F}$: • no kernel is sample-efficient;
 - Exists a neural network that is sample-efficient.

Separation between NN and kernel to keend method is a linear mention with an embedding $\phi: \mathcal{R}^d \rightarrow \mathcal{M}$, Hilbert f turns an element $f \in \mathcal{H}$ into a prediction function $\mathcal{Y} = \langle f, \phi(x) \rangle$ The method uses sample, $\{x_i\}_{i=1}^{n}$, $x_i \in \mathbb{D}^d$ observes $\{y_i\}_{i=1}^{n}$, $(x_i)_{i=1}^{n}$, $x_i \in \mathbb{D}^d$ $f \in S_i$ and $(\Phi(x_i))_{i=1}^{n}$, $\gamma \in \mathbb{D}^d$ $f \in S_i$ and $(\Phi(x_i), f > j + \chi) \|f\|^2$ $f \in \mathcal{A}$, $f \in \mathcal{A}$

This: D a dass of functions CE(C: P-)P) and a distribution over D'sit, Separation between NN and kernel 2) If Kevnel method, HCEC, given Si = C(Xi) To orthogonal of Frank of $E_{X} \sim M \left[\left[C(X) - \langle f, \xi(x) \rangle \right] \right] \leq \frac{1}{9}$ then $u \neq 2$ I simple procedure, that can adjust the true (as long as had $\left(\begin{array}{c} 1 \\ 1 \end{array} \right)$ A the procedure can be simulated by a neurod not work of GI)

Pf: M: uniform distribution our f-1,15d 2 d element **Separation between NN and kernel** $C = \int C_{s} = \prod_{s \in S} X_{s} \int SC \{1, \dots, d\} \right)$ $Pf \text{ of } Pavf ii) \text{ choose } a \text{ basis} \begin{pmatrix} -1 \\ i \\ i \end{pmatrix} \begin{pmatrix} -1 \\ i \\ i \end{pmatrix} \dots \begin{pmatrix} 1 \\ i \\ i \end{pmatrix}$ $=) y_{1}^{*} = (g(P_{1}), jf \text{ i} \in S, y_{1}^{*} = -1)$ $i \in C \quad y_{1}^{*} = -1$ =) Khan uhether j is ju Sor not) identify (1 =) leaven (5]

Separation between NN and kernel Parti) Cis a basis for Sf: Stild 223 with distribution M. $\begin{array}{c} F_{X-M} \left[C_{\mathcal{G}}(X) \cdot (\mathcal{G}'(X)) = \left\{ \begin{array}{c} 0 & \text{if } \mathcal{J} \neq \mathcal{J}' \\ 1 & \text{if } \mathcal{J} = \mathcal{J}' \end{array} \right] \\ \vdots & F_{Y-M} \left[C_{\mathcal{G}}(X) \cdot (\mathcal{J}'(X)) = \left\{ \begin{array}{c} 0 & \text{if } \mathcal{J} \neq \mathcal{J}' \\ 1 & \text{if } \mathcal{J} = \mathcal{J}' \end{array} \right] \\ \end{array}$ (noal: $f_{K-M} \left[\left(\int_{S^{-1}} (Y) - \langle f \rangle \phi(Y) \rangle \right)^2 \right]$ 1) since $f \in Span \left(\phi(K_i) \right)_{j=1}^{M}$ $f = \stackrel{M}{=} O(i \phi(X_i)), f(Y) = \stackrel{M}{=} O(i \langle \phi(K_i) \rangle \phi(Y))$ $X \rightarrow (K_i) / \xi(K)$ $= \sum_{f \in [d]} \lambda_{i_{f}} \int_{f} (f(x))$

Separation between NN and kernel $E_{X-M} \left[\left(\sum_{s}^{*} (X) - (X) + (X) \right)^{2} \right]$ $= \mathbb{E}_{X-M} \left[\left((S^{*}(X) - Z \stackrel{>}{\geq} \mathcal{O}_{1} \stackrel{>}{\cdot} \mathcal{H}_{i}, S \stackrel{>}{(S^{(X)})} \right) \right]$ $= \left(1 - \frac{y}{z_{i}} \left(1 - \frac{y}{z_{i}}\right)^{2} + \frac{y}{z_{i}} \left(\frac{y}{z_{i}} \left(1 - \frac{y}{z_{i}}\right)^{2}\right)^{2} + \frac{y}{z_{i}} \left(\frac{y}{z_{i}}\right)^{2} + \frac{y}{z_{i}} \left(\frac{y}{z_{i}}\right)^{2}\right)^{2}$ by assumption every 54 $= \int \left(\left(- \frac{9}{5} \left(1 \right) \right)^2 \left(- \frac{1}{5} \right)^2 \left(- \frac{1}{5}$

Separation between NN and kernel

 $\Lambda : 2^d \times \eta$ Notations) L 54, 54 $A = n \times 2^{d}$ = $\frac{y}{2}$ $\frac{h_{1,s}}{h_{1,s}}$ $\frac{h_{1,s}}{h_{1,s}}$ Ai, St = Mi, St $SL = \Lambda A : 2^{d} X 2^{d} f Van K - M$ $(|- \Sigma_{5',5'}|^2 \leq \frac{1}{2} \rightarrow \Sigma_{5',5'} \sim \frac{4}{7} q$ $\sum_{s=1}^{2} \sum_{s=1}^{2} \sum_{s$ Ì L: 20 x7d

Separation between NN and kernel SZ = ling(SZ) + SZ', SZ': off-diagond $\frac{11 \text{ Silf}^{2}}{29} = \sum eigen^{2}(S)$ $= \sum S \ln n \text{ at most} \frac{2^{4}}{4} eigenvalue \text{ }$ $= \sum S \frac{1}{29} \ln n \text{ at most} \frac{2^{4}}{4} eigenvalue \text{ }$ =) (sufficiency subspace with eigenvalue) $c_{\frac{3}{2}}$ which has dimension at lense $\frac{3}{42}$ of KK subspace YKE subspare $\| \int x \|_{2} = \| \int \log (\int x + \int x \|_{2}$ $\int X \in Span(SL) = \sum_{j=1}^{n} |J| diag(SL) \times |I_{2}| |SK|_{2}$



Belkin, Hsu, Ma, Mandal '18

- There are cases where the model gets bigger, yet the (test!) loss goes down, sometimes even lower than in the classical "under-parameterized" regime.
- Complexity: number of parameters.

Widespread phenomenon, across architectures (Nakkiran et al. '19):



(a) **CIFAR-100.** There is a peak in test error even with no label noise.



(b) **CIFAR-10.** There is a "plateau" in test error around the interpolation point with no label noise, which develops into a peak for added label noise.

Widespread phenomenon, across architectures (Nakkiran et al. '19):



Widespread phenomenon, also in kernels (can be formally proved in some concrete settings [Mei and Montanari '20]), random forests, etc.



Also in other quantities such as train time, dataset, etc (Nakkiran et al. '19):



Figure 2: Left: Test error as a function of model size and train epochs. The horizontal line corresponds to model-wise double descent-varying model size while training for as long as possible. The vertical line corresponds to epoch-wise double descent, with test error undergoing double-descent as train time increases. **Right** Train error of the corresponding models. All models are Resnet18s trained on CIFAR-10 with 15% label noise, data-augmentation, and Adam for up to 4K epochs.

Optimal regularization can mitigate double descent [Nakkiran et al. '21]:



Optimal regularization can mitigate double descent [Nakkiran et al. '21]:





a) Test Classification Error vs. Number of Trainng Samples.

(b) Test Classification Error vs. Model Size (Number of Random Features).

Implicit Regularization

Different optimization algorithm

→ Different bias in optimum reached

- ➔ Different Inductive bias
 - ➔ Different generalization properties



Implicit Bias

Margin:

- Linear predictors:
 - Gradient descent, mirror descent, natural gradient descent, steepest descent, etc maximize margins with respect to different norms.
- Non-linear:
 - Gradient descent maximizes margin for homogeneous neural networks.
 - Low-rank matrix sensing: gradient descent finds a low-rank solution.